











SN74CBTLV3383

ZHCSJ64H -MARCH 1998-REVISED DECEMBER 2018

# SN74CBTLV3383 低电压 10 位 FET 总线交换开关

### 1 特性

- 两个端口间使用 5Ω 开关连接
- 支持在数据 I/O 端口进行轨至轨开关
- I<sub>off</sub> 支持局部断电模式运行
- 锁存性能超过 250mA, 符合 JESD 17 规范
- ESD 保护性能超出 JESD 22 标准
  - 2000V 人体放电模型 (A114-A)
  - 200V 机器模型 (A115-A)

### 2 应用

- 游戏
- 机架式服务器
- 通信板

### 3 说明

SN74CBTLV3383 可提供十位高速总线开关或交换。 此开关具有低通态电阻,可以在最短传播延迟情况下建 立连接。

该器件作为 10 位总线开关或 5 位总线交换器运行,可将 A 对信号和 B 对信号进行交换。总线交换功能会在BX 高、BE 低时选中。

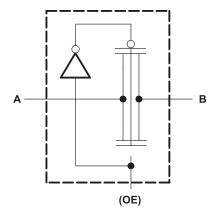
该器件完全 适用于 使用 l<sub>off</sub> 的局部断电应用。l<sub>off</sub> 特性确保在关断时防止损坏电流通过器件回流。该器件可在关断时提供隔离。

### 器件信息<sup>(1)</sup>

器件型号	封装	封装尺寸 (标称值)		
	QSOP - DBQ	8.65mm x 3.90mm		
SN74CBTLV3383	SOIC - DW	15.4mm x 7.50mm		
	TSSOP - PW	7.80mm x 4.40mm		
	TVSOP - DGV	5.00mm x 4.40mm		

(1) 如需了解所有可用封装,请参阅数据表末尾的可订购产品附录。

#### 每个 FET 开关的简化原理图





$\neg$	$\rightarrow$
-	ملب
_	

1 2 3	特性	8.4 Device Functional Modes
4	修订历史记录 2	10 Power Supply Recommendations
5 6	Pin Configuration and Functions	11 Layout
Ū	6.1 Absolute Maximum Ratings       4         6.2 ESD Ratings       4         6.3 Recommended Operating Conditions       4         6.4 Thermal Information       4         6.5 Electrical Characteristics       5         6.6 Switching Characteristics       5	11.1 Layout Guidelines       1         11.2 Layout Example       1         12 器件和文档支持       1         12.1 文档支持       1         12.2 接收文档更新通知       1         12.3 社区资源       1
7	Parameter Measurement Information 6	12.4 商标1
8	Detailed Description         7           8.1 Overview         7           8.2 Functional Block Diagram         7           8.3 Feature Description         7	12.5 静电放电警告

### 4 修订历史记录

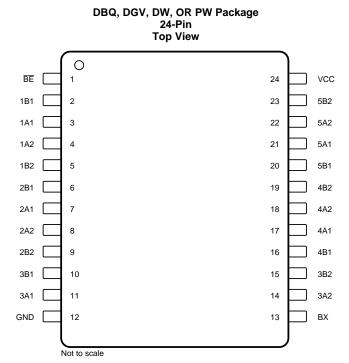
注: 之前版本的页码可能与当前版本有所不同。

### Changes from Revision G (October 2003) to Revision H

**Page** 



# 5 Pin Configuration and Functions



### **Pin Functions**

	PIN	1/0	DECORPORTION
NAME			DESCRIPTION
BE	1	I	Active low enable: When this pin is high, all switches are turned off. When this pin is low, BX pin controls the signal path selection.
1B1	2	I/O	Signal path. Can be an input or output
1A1	3	I/O	Signal path. Can be an input or output
1A2	4	I/O	Signal path. Can be an input or output
1B2	5	I/O	Signal path. Can be an input or output
2B1	6	I/O	Signal path. Can be an input or output
2A1	7	I/O	Signal path. Can be an input or output
2A2	8	I/O	Signal path. Can be an input or output
2B2	9	I/O	Signal path. Can be an input or output
3B1	10	I/O	Signal path. Can be an input or output
3A1	11	I/O	Signal path. Can be an input or output
GND	12	Р	Ground (0V) reference
BX	13	1	Controls state of switches
3A2	14	I/O	Signal path. Can be an input or output
3B2	15	I/O	Signal path. Can be an input or output
4B1	16	I/O	Signal path. Can be an input or output
4A1	17	I/O	Signal path. Can be an input or output
4A2	18	I/O	Signal path. Can be an input or output
4B2	19	I/O	Signal path. Can be an input or output
5B1	20	I/O	Signal path. Can be an input or output
5A1	21	I/O	Signal path. Can be an input or output
5A2	22	I/O	Signal path. Can be an input or output
5B2	23	I/O	Signal path. Can be an input or output
V <sub>CC</sub>	24	Р	Positive power supply.



# 6 Specifications

### 6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

		MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage range	-0.5	4.6	V
VI	Input voltage range	-0.5	4.6	V
	Continuous channel current .		128	mA
I <sub>IK</sub>	Input clamp current, V <sub>I/O</sub> < 0		-50	mA
T <sub>stg</sub>	Storage temperature	-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### 6.2 ESD Ratings

			VALUE	UNIT
		Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 (1)	±2000	
V <sub>(ESD)</sub>	Electrostatic discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 <sup>(2)</sup>	±1000	V

JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process. JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

### 6.3 Recommended Operating Conditions<sup>(1)</sup>

over operating free-air temperature range (unless otherwise noted)

			MIN	NOM	MAX	UNIT
$V_{CC}$	Supply voltage		2.3		3.6	V
V	Lligh level central input valtage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7			V
V <sub>IH</sub>	High-level control input voltage	$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2			V
V	Low lovel control input voltage	V <sub>CC</sub> = 2.3 V to 2.7 V			0.7	V
V <sub>IL</sub>	Low-level control input voltage	V <sub>CC</sub> = 2.7 V to 3.6 V			8.0	V
T <sub>A</sub>	Operating free-air temperature		-40		85	°C

<sup>(1)</sup> All unused control inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*.

### 6.4 Thermal Information

		SN74CBTLV3383					
THERMAL METRIC <sup>(1)</sup>		DBQ (QSOP)	DVG (TVSOP)	DW (SPIC)	PW (TSSOP)	UNIT	
		24 PINS	24 PINS	24 PINS	24 PINS		
$R_{\theta JA}$	Junction-to-ambient thermal resistance	86.6	105.6	66.6	90.1	°C/W	
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	40.5	36.9	36.7	34.12	°C/W	
$R_{\theta JB}$	Junction-to-board thermal resistance	40.8	51.1	36.6	45.2	°C/W	
ΨЈТ	Junction-to-top characterization parameter	7.8	2.6	13.1	2.8	°C/W	
ΨЈВ	Junction-to-board characterization parameter	40.4	50.6	36.4	44.8	°C/W	
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	n/a	n/a	n/a	n/a	°C/W	

For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.



#### 6.5 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS			MIN	TYP <sup>(1)</sup>	MAX	UNIT
V <sub>IK</sub>	Clamp current	V <sub>CC</sub> = 3 V	$I_1 = -18 \text{ mA}$				-1.2	V
I <sub>I</sub>	Input current	V <sub>CC</sub> = 3.6 V	V <sub>I</sub> = V <sub>CC</sub> or GND		-1		1	μΑ
I <sub>off</sub>	Partial power down mode operation	V <sub>CC</sub> = 0 V	V <sub>I</sub> or V <sub>IO</sub> = 0 to 3.6 V				10	μΑ
I <sub>CC</sub>	Supply current	$V_{CC} = 3.6$	$I_O = 0$ , $V_I = V_{CO}$	or GND			10	μΑ
ΔI <sub>CC</sub> <sup>(2)</sup>	Supply current - Control inputs	V <sub>CC</sub> = 3.6 V	One input at 3V Other inputs at VCC or GND				300	μΑ
C <sub>I</sub>	Input Capacitance - Control inputs	V <sub>I</sub> = 3 V or 0	V <sub>i</sub> = 3 V or 0			3.5		pF
C <sub>IO(OFF)</sub>	Input to output capacitance	$V_O = 3 \text{ V or } 0$	$\overline{\text{BE}} = V_{\text{CC}}$			13.5		pF
		V <sub>CC</sub> = 2.3 V	., .	I <sub>I</sub> = 64 mA		5	8	Ω
		TYP at VCC = 2.5 V	$V_I = 0$	I <sub>I</sub> = 24 mA		5	8	Ω
(3)			V <sub>I</sub> = 1.7 V	I <sub>I</sub> = 15 mA		27	40	Ω
r <sub>(on)</sub> (3)	On-state resistance		V <sub>I</sub> = 0	I <sub>I</sub> = 64 mA		5	7	Ω
		V <sub>CC</sub> = 3 V		I <sub>I</sub> = 24 mA		5	7	Ω
			V <sub>I</sub> = 2.4 V	I <sub>I</sub> = 15 mA		10	15	Ω

### 6.6 Switching Characteristics

over operating free-air temperature range (unless otherwise noted)

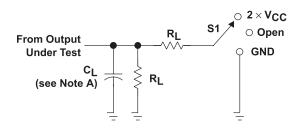
PARAMETER		TEST CONDITIONS		$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$		$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		UNIT
		FROM (INPUT)	TO (OUTPUT)	MIN	MAX	MIN	MAX	UNII
t <sub>pd</sub> (1)	Propagation delay time	A or B	Bo or A		0.15		0.25	ns
t <sub>pd</sub>	Propagation delay time	BX	A or B	1.5	5.8	1.5	4.7	ns
t <sub>en</sub>	Enable time	BE	A or B	1.5	5.3	1.5	4.7	ns
t <sub>dis</sub>	Disable time	BE	A or B	1	6	1	6	ns

<sup>(1)</sup> The propagation delay is the calculated RC time constant of the typical on-state resistance of the switch and the specified load capacitance, when driven by an ideal voltage source (zero output impedance).

All typical values are at  $V_{CC}$  = 3.3 V (unless otherwise noted),  $T_A$  = 25°C This is the increase in supply current for each input that is at the specified voltage level, rather than  $V_{CC}$  or GND. Measured by the voltage drop between the A and B terminals at the indicated current through the switch. On-state resistance is determined by the lower of the voltages of the two (A or B) terminals.



### 7 Parameter Measurement Information



TEST	S1
tPLH/tPHL	Open
tPLZ/tPZL	2 × V <sub>CC</sub>
tPHZ/tPZH	GND

V <sub>CC</sub>	CL	RL	${f v}_\Delta$
2.5 V ±0.2 V	30 pF	500 Ω	0.15 V
3.3 V ±0.3 V	50 pF	500 Ω	0.3 V

图 1. Load Current

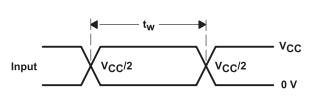


图 2. Voltage Waveforms Pulse Duration

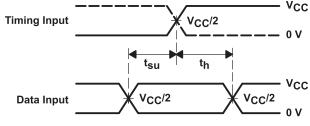


图 3. Voltage Waveforms Setup and Hold Times

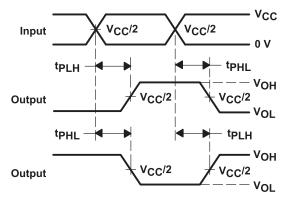


图 4. Voltage Waveforms Propagation Delay Times Inverting and Noninverting Outputs

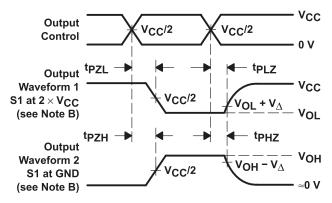


图 5. Voltage Waveforms Enable And Disable Times Low- and High-Level Enabling

#### Notes:

- A. C<sub>L</sub> includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O = 50 \Omega$ ,  $t_r \leq$  2 ns,  $t_f \leq$  2 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. t<sub>PLZ</sub> and t<sub>PHZ</sub> are the same as t<sub>dis</sub>.
- F. t<sub>PZL</sub> and t<sub>PZH</sub> are the same as t<sub>en</sub>.
- G. t<sub>PLH</sub> and t<sub>PHL</sub> are the same as t<sub>pd</sub>.
- H. H. All parameters and waveforms are not applicable to all devices.

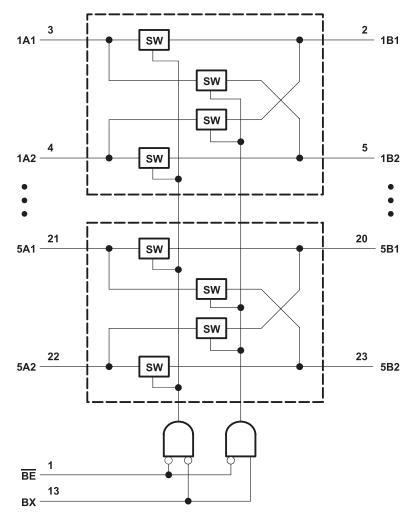


### 8 Detailed Description

#### 8.1 Overview

The SN74CBTLV3383 device is a 10-bit high-speed bus exchange FET switch. The low ONstate resistance of the switch allows connections to be made with minimal propagation delay. The select (BX) input controls the data flow. The FET multiplexers and demultiplexers are disabled when the output-enable (BE) input is high. This device is fully specified for partial-power-down applications using loff. The loff feature ensures that damaging current will not backflow through the device when it is powered down. The device has isolation during power off. To ensure the high-impedance state during power up or power down, OE should be tied to VCC through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

### 8.2 Functional Block Diagram



### 8.3 Feature Description

**Bidirectional Operation** 

The SN74CBTLV3383 conducts equally well from source (xA1, xA2) to drain (xB1,xB2). Each channel has very similar characteristics in both directions and supports both analog and digital signals.

Rail-to-rail switching

The SN74CBTLV3383 will support signals on the I/O path across the full supply range 0 to V<sub>CC</sub>



### 8.4 Device Functional Modes

Shows the functional modes of the SN74CBTLV3383.

表 1. Function Table

INP	UTS	INPUTS-OUTPUTS				
BE	вх	1A1-5A1	1A2-5A2			
L	L	1B1-5B1	1B2-5B2			
L	Н	1B2-5B2	1B1–5B1			
Н	Х	Z	Z			



# 9 Application and Implementation

注

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

### 9.1 Application Information

The SN74CBTLV3383 device operates as a 10-bit bus switch or as a 5-bit bus exchanger, which provides swapping of the A and B pairs of signals. The bus-exchange function is selected when BX is high, and BE is low. The application shown here is a 5-bit bus being multiplexed between two devices. The BE and BX pins are used to control the chip from the bus controller. This is a generic example, and could apply to many situations.

### 9.2 Typical Application

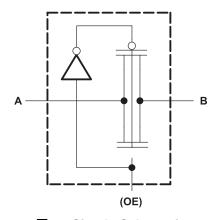


图 6. Simple Schematic

#### 9.2.1 Design Requirements

- 1. Recommended Input Conditions:
  - For specified high and low levels, see V<sub>IH</sub> and V<sub>IL</sub> in Recommended Operating Conditions.
  - Inputs and outputs are overvoltage tolerant slowing them to go as high as 4.6 V at any valid VCC.
- 2. Recommended Output Conditions:
  - Load currents should not exceed ±128 mA per channel.
- 3. Frequency Selection Criterion:
  - Maximum frequency tested is 200 MHz.

#### 9.2.2 Detailed Design Procedure

The SN74CBTLV3383 can be operated without any external components. All inputs signals passing through the switch must fall within the recommend operating conditions of the SN74CBTLV3383 including signal range and continuous current. For this design example, with a supply of 3.3 V, the signals can range from 0 V to 3.3 V when the device is powered. The max continuous current can be 128 mA.



# 10 Power Supply Recommendations

The SN74CBTLV3383 operates across a wide supply range of 2.3 V to 3.6 V. Do not exceed the absolute maximum ratings because stresses beyond the listed ratings can cause permanent damage to the devices. Power-supply bypassing improves noise margin and prevents switching noise propagation from the VDD supply to other components. Good power-supply decoupling is important to achieve optimum performance. For improved supply noise immunity, use a supply decoupling capacitor ranging from 0.1  $\mu F$  to 10  $\mu F$  from VDD to ground. Place the bypass capacitors as close to the power supply pins of the device as possible using low-impedance connections. TI recommends using multi-layer ceramic chip capacitors (MLCCs) that offer low equivalent series resistance (ESR) and inductance (ESL) characteristics for power-supply decoupling purposes. For very sensitive systems, or for systems in harsh noise environments, avoiding the use of vias for connecting the capacitors to the device pins may offer superior noise immunity. The use of multiple vias in parallel lowers the overall inductance and is beneficial for connections to ground planes.

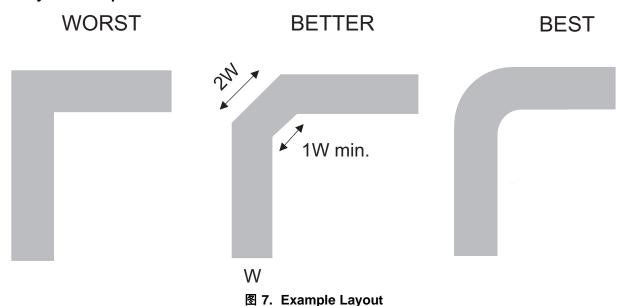


### 11 Layout

### 11.1 Layout Guidelines

Reflections and matching are closely related to the loop antenna theory but are different enough to be discussed separately from the theory. When a PCB trace turns a corner at a 90° angle, a reflection can occur. A reflection occurs primarily because of the change of width of the trace. At the apex of the turn, the trace width increases to 1.414 times the width. This increase upsets the transmission-line characteristics, especially the distributed capacitance and self–inductance of the trace which results in the reflection. Not all PCB traces can be straight and therefore some traces must turn corners. Figure 4 shows progressively better techniques of rounding corners. Only the last example (BEST) maintains constant trace width and minimizes reflections.

### 11.2 Layout Example





#### 12 器件和文档支持

#### 12.1 文档支持

#### 12.2 接收文档更新通知

要接收文档更新通知,请导航至 Tl.com.cn 上的器件产品文件夹。单击右上角的通知我进行注册,即可每周接收产品信息更改摘要。有关更改的详细信息,请查看任何已修订文档中包含的修订历史记录。

#### 12.3 社区资源

下列链接提供到 TI 社区资源的连接。链接的内容由各个分销商"按照原样"提供。这些内容并不构成 TI 技术规范,并且不一定反映 TI 的观点;请参阅 TI 的 《使用条款》。

TI E2E™ 在线社区 TI 的工程师对工程师 (E2E) 社区。此社区的创建目的在于促进工程师之间的协作。在 e2e.ti.com 中,您可以咨询问题、分享知识、拓展思路并与同行工程师一道帮助解决问题。

设计支持 71 参考设计支持 可帮助您快速查找有帮助的 E2E 论坛、设计支持工具以及技术支持的联系信息。

#### 12.4 商标

E2E is a trademark of Texas Instruments.

All other trademarks are the property of their respective owners.

#### 12.5 静电放电警告



ESD 可能会损坏该集成电路。德州仪器 (TI) 建议通过适当的预防措施处理所有集成电路。如果不遵守正确的处理措施和安装程序,可能会损坏集成电路。

**ESD** 的损坏小至导致微小的性能降级,大至整个器件故障。 精密的集成电路可能更容易受到损坏,这是因为非常细微的参数更改都可能会导致器件与其发布的规格不相符。

### 12.6 术语表

SLYZ022 — TI 术语表。

这份术语表列出并解释术语、缩写和定义。

### 13 机械、封装和可订购信息

以下页面包含机械、封装和可订购信息。这些信息是指定器件的最新可用数据。数据如有变更,恕不另行通知,且 不会对此文档进行修订。如需获取此数据表的浏览器版本,请查阅左侧的导航栏。 www.ti.com

23-May-2025

#### PACKAGING INFORMATION

Orderable part number	Status	Material type	Package   Pins	Package qty   Carrier	RoHS	Lead finish/	MSL rating/	Op temp (°C)	Part marking
	(1)	(2)			(3)	Ball material	Peak reflow		(6)
						(4)	(5)		
SN74CBTLV3383DBQR	Active	Production	SSOP (DBQ)   24	2500   LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	CBTLV3383
SN74CBTLV3383DBQR.B	Active	Production	SSOP (DBQ)   24	2500   LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	CBTLV3383
SN74CBTLV3383DGVR	Active	Production	TVSOP (DGV)   24	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CL383
SN74CBTLV3383DGVR.B	Active	Production	TVSOP (DGV)   24	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CL383
SN74CBTLV3383DW	Active	Production	SOIC (DW)   24	25   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CBTLV3383
SN74CBTLV3383DW.B	Active	Production	SOIC (DW)   24	25   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CBTLV3383
SN74CBTLV3383DWE4	Active	Production	SOIC (DW)   24	25   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CBTLV3383
SN74CBTLV3383DWR	Active	Production	SOIC (DW)   24	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CBTLV3383
SN74CBTLV3383DWR.B	Active	Production	SOIC (DW)   24	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CBTLV3383
SN74CBTLV3383PW	Active	Production	TSSOP (PW)   24	60   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CL383
SN74CBTLV3383PW.B	Active	Production	TSSOP (PW)   24	60   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CL383
SN74CBTLV3383PWR	Active	Production	TSSOP (PW)   24	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CL383
SN74CBTLV3383PWR.B	Active	Production	TSSOP (PW)   24	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CL383

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

<sup>(2)</sup> Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

<sup>(3)</sup> RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

<sup>(4)</sup> Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.



# **PACKAGE OPTION ADDENDUM**

www.ti.com 23-May-2025

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

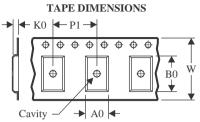
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

# **PACKAGE MATERIALS INFORMATION**

www.ti.com 24-Jul-2025

### TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74CBTLV3383DBQR	SSOP	DBQ	24	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
SN74CBTLV3383DGVR	TVSOP	DGV	24	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74CBTLV3383DWR	SOIC	DW	24	2000	330.0	24.4	10.75	15.7	2.7	12.0	24.0	Q1

www.ti.com 24-Jul-2025



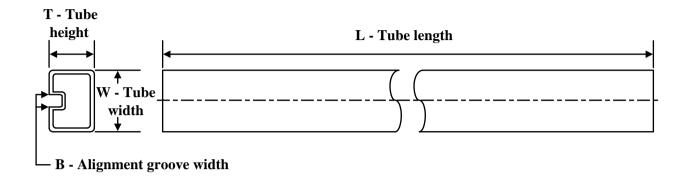
### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74CBTLV3383DBQR	SSOP	DBQ	24	2500	353.0	353.0	32.0
SN74CBTLV3383DGVR	TVSOP	DGV	24	2000	353.0	353.0	32.0
SN74CBTLV3383DWR	SOIC	DW	24	2000	350.0	350.0	43.0

# **PACKAGE MATERIALS INFORMATION**

www.ti.com 24-Jul-2025

### **TUBE**

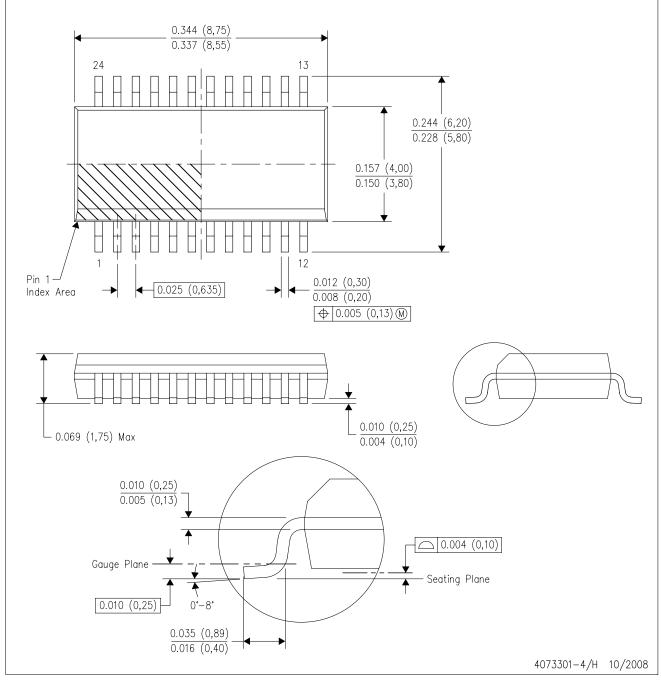


\*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
SN74CBTLV3383DW	DW	SOIC	24	25	506.98	12.7	4826	6.6
SN74CBTLV3383DW.B	DW	SOIC	24	25	506.98	12.7	4826	6.6
SN74CBTLV3383DWE4	DW	SOIC	24	25	506.98	12.7	4826	6.6
SN74CBTLV3383PW	PW	TSSOP	24	60	530	10.2	3600	3.5
SN74CBTLV3383PW.B	PW	TSSOP	24	60	530	10.2	3600	3.5

DBQ (R-PDSO-G24)

### PLASTIC SMALL-OUTLINE PACKAGE

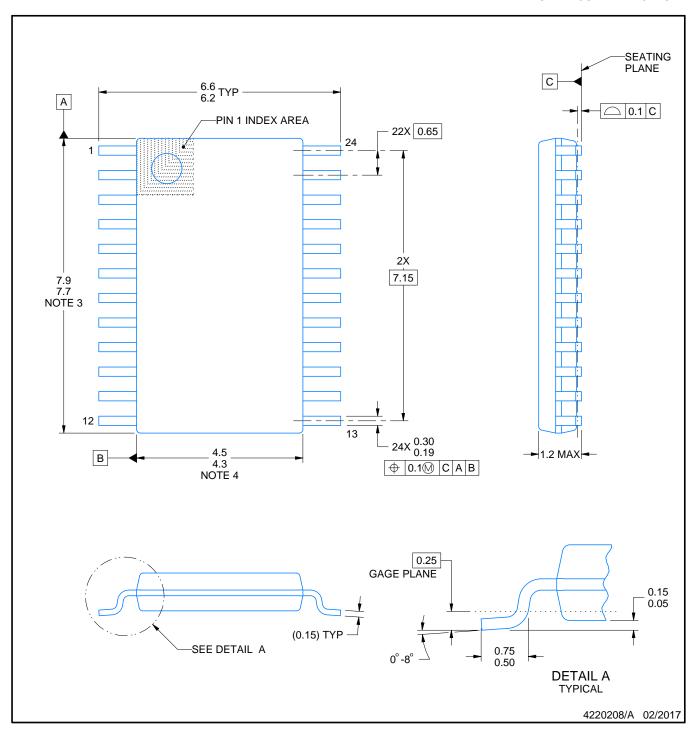


NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15) per side.
- D. Falls within JEDEC MO-137 variation AE.







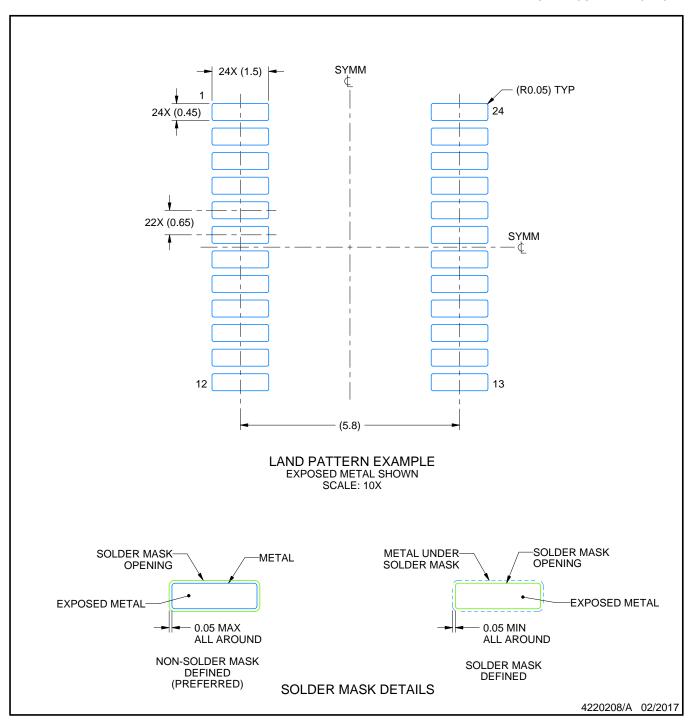
#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



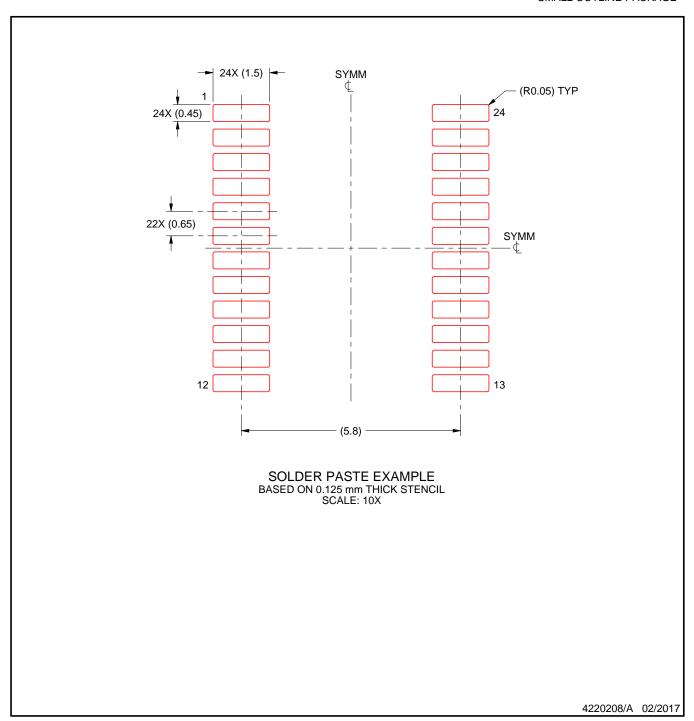


NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



DW (R-PDSO-G24)

# PLASTIC SMALL OUTLINE

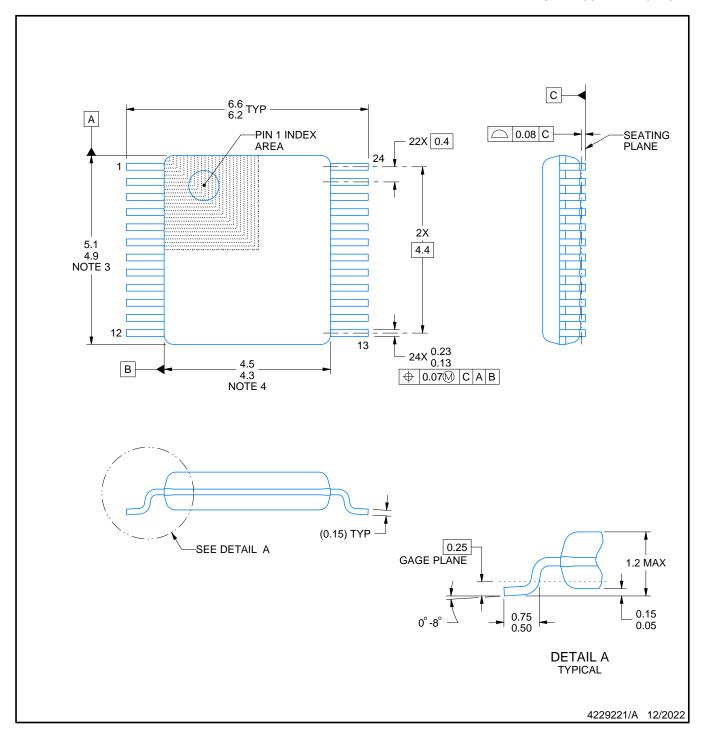


NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AD.







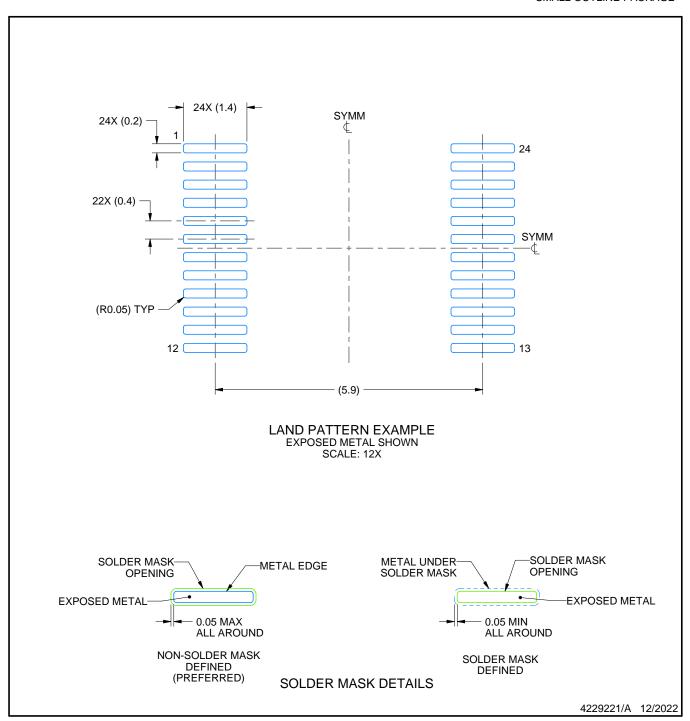
#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



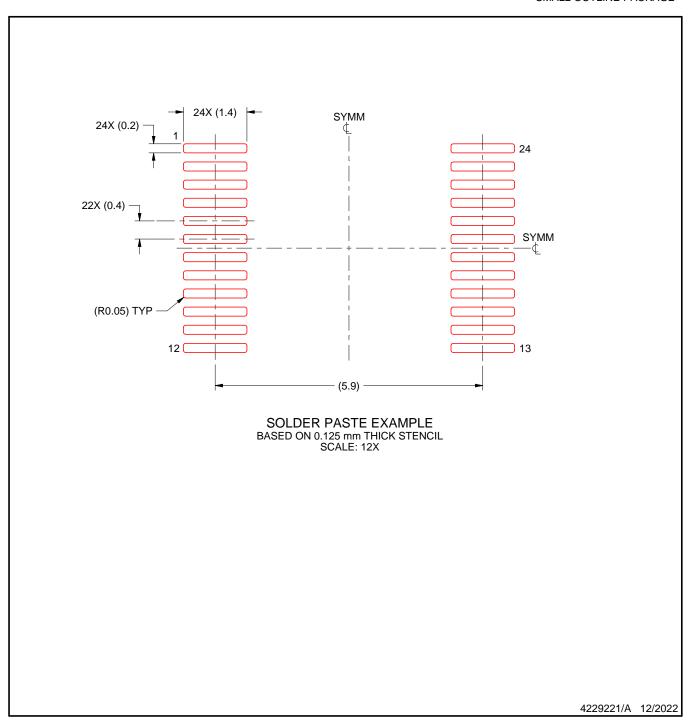


NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



### 重要通知和免责声明

TI"按原样"提供技术和可靠性数据(包括数据表)、设计资源(包括参考设计)、应用或其他设计建议、网络工具、安全信息和其他资源,不保证没有瑕疵且不做出任何明示或暗示的担保,包括但不限于对适销性、某特定用途方面的适用性或不侵犯任何第三方知识产权的暗示担保。

这些资源可供使用 TI 产品进行设计的熟练开发人员使用。您将自行承担以下全部责任:(1) 针对您的应用选择合适的 TI 产品,(2) 设计、验证并测试您的应用,(3) 确保您的应用满足相应标准以及任何其他功能安全、信息安全、监管或其他要求。

这些资源如有变更,恕不另行通知。TI 授权您仅可将这些资源用于研发本资源所述的 TI 产品的相关应用。 严禁以其他方式对这些资源进行复制或展示。您无权使用任何其他 TI 知识产权或任何第三方知识产权。您应全额赔偿因在这些资源的使用中对 TI 及其代表造成的任何索赔、损害、成本、损失和债务,TI 对此概不负责。

TI 提供的产品受 TI 的销售条款或 ti.com 上其他适用条款/TI 产品随附的其他适用条款的约束。TI 提供这些资源并不会扩展或以其他方式更改 TI 针对 TI 产品发布的适用的担保或担保免责声明。

TI 反对并拒绝您可能提出的任何其他或不同的条款。

邮寄地址:Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 版权所有 © 2025,德州仪器 (TI) 公司